



KATHOLIEKE UNIVERSITEIT  
**LEUVEN**



# Passivation of Si and CIGS surfaces



- Part I:  $\text{Al}_2\text{O}_3$  passivation for Si PERx
- Part II: PERC meets CIGS - PercIGS



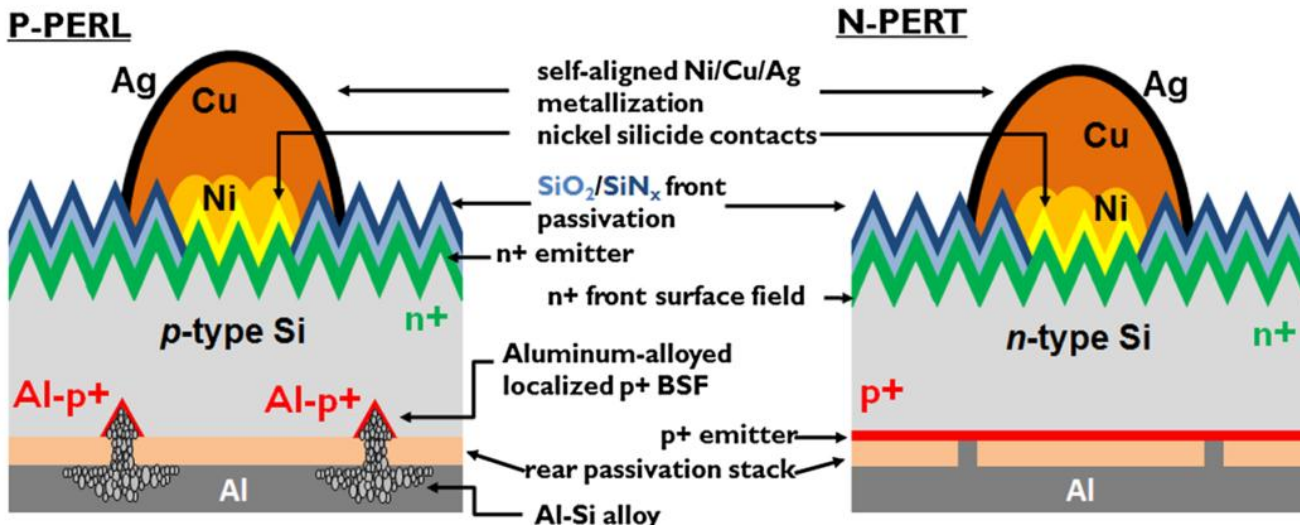
Vetenskapsrådet

*Bart Vermang et al.*

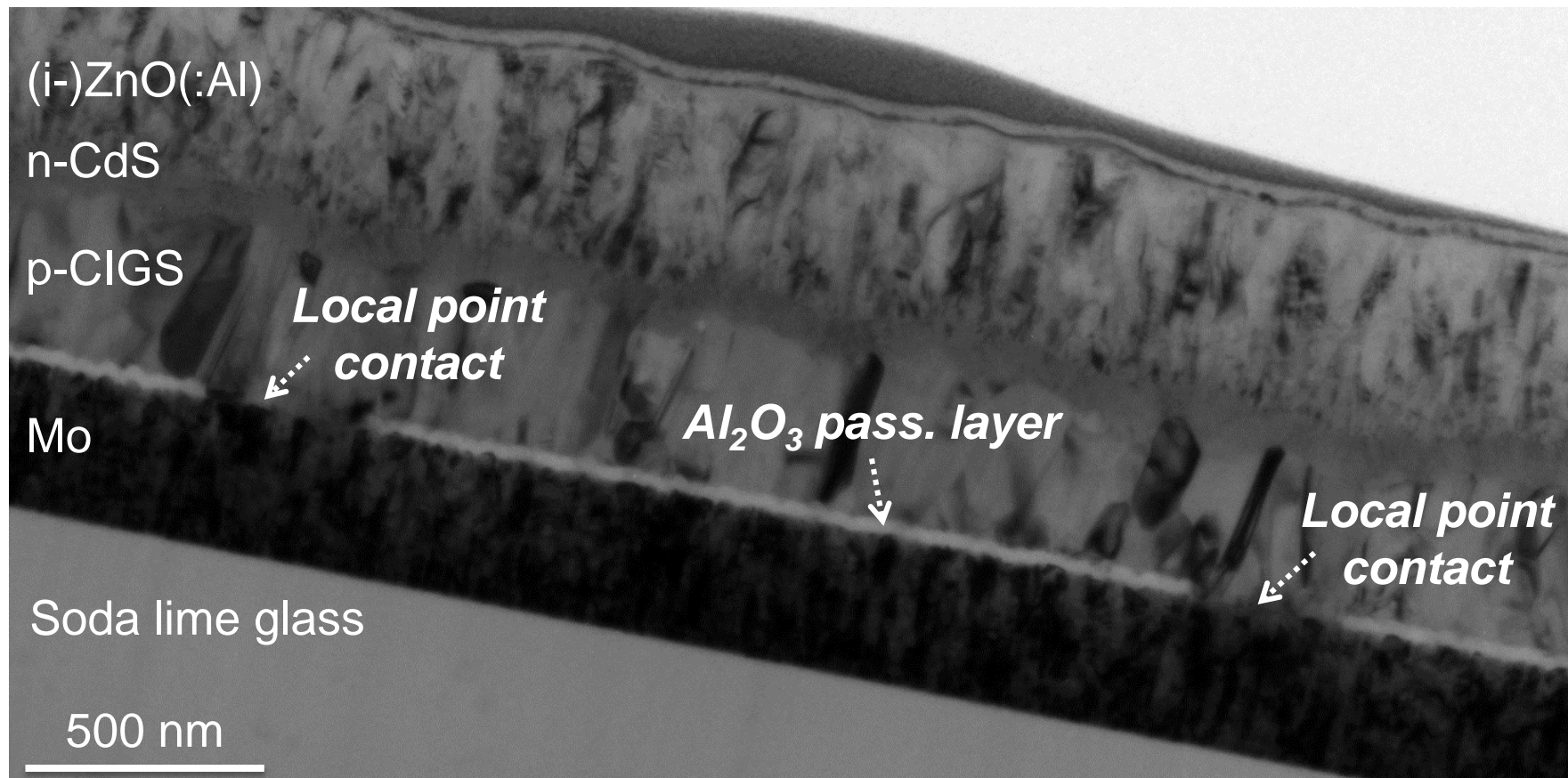


# Part I: Al<sub>2</sub>O<sub>3</sub> passivation for Si PERx

- p-type PERL ≥ 20.5 %
- n-type PERT ≥ 21.5 %
- Rear passivation stack = ALD Al<sub>2</sub>O<sub>3</sub> (+ capping)



## Part II: PERC meets CIGS - PercIGS





# Leuven, Belgium



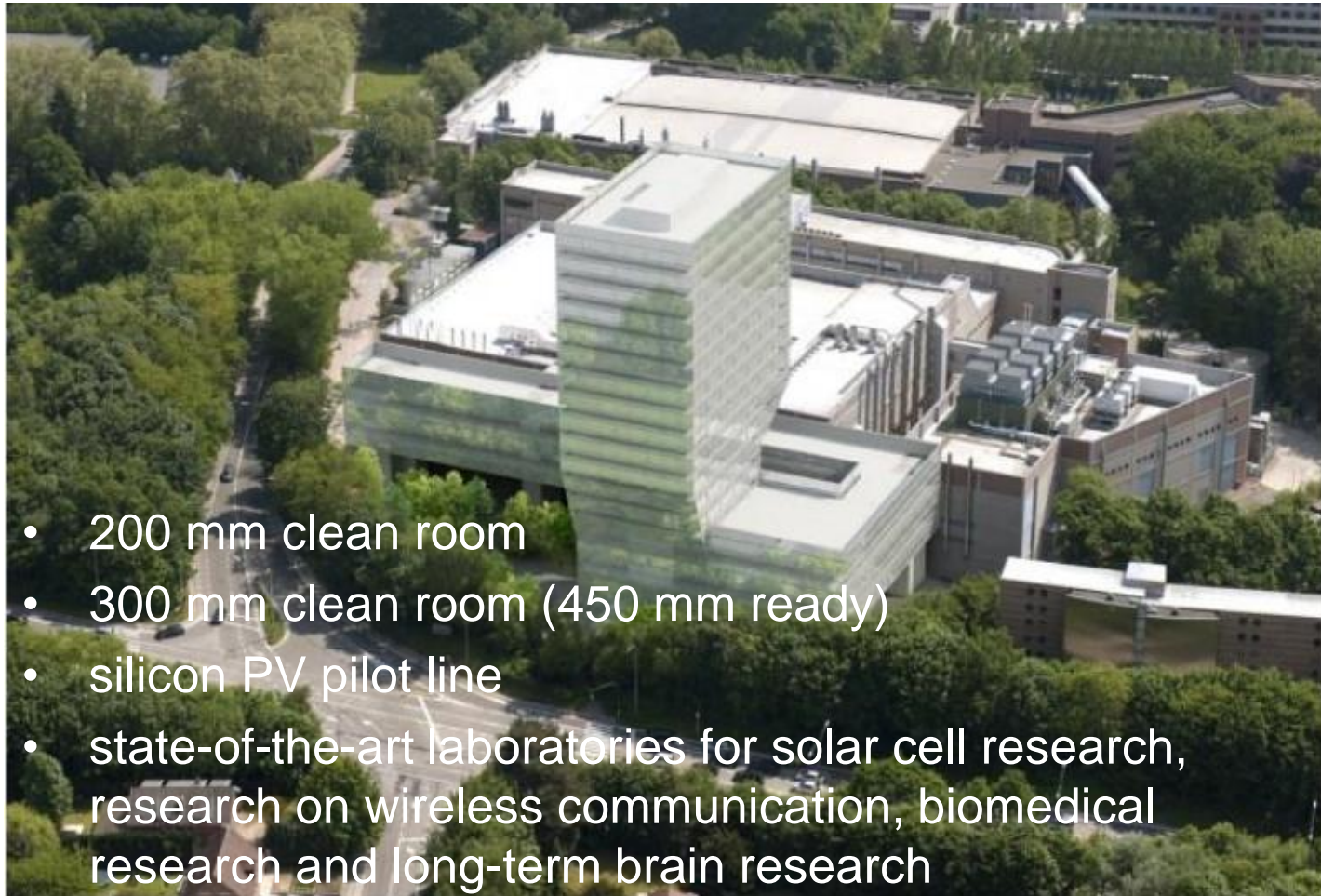


# Interuniversity Micro-Electronics Centre (imec), Leuven, Belgium





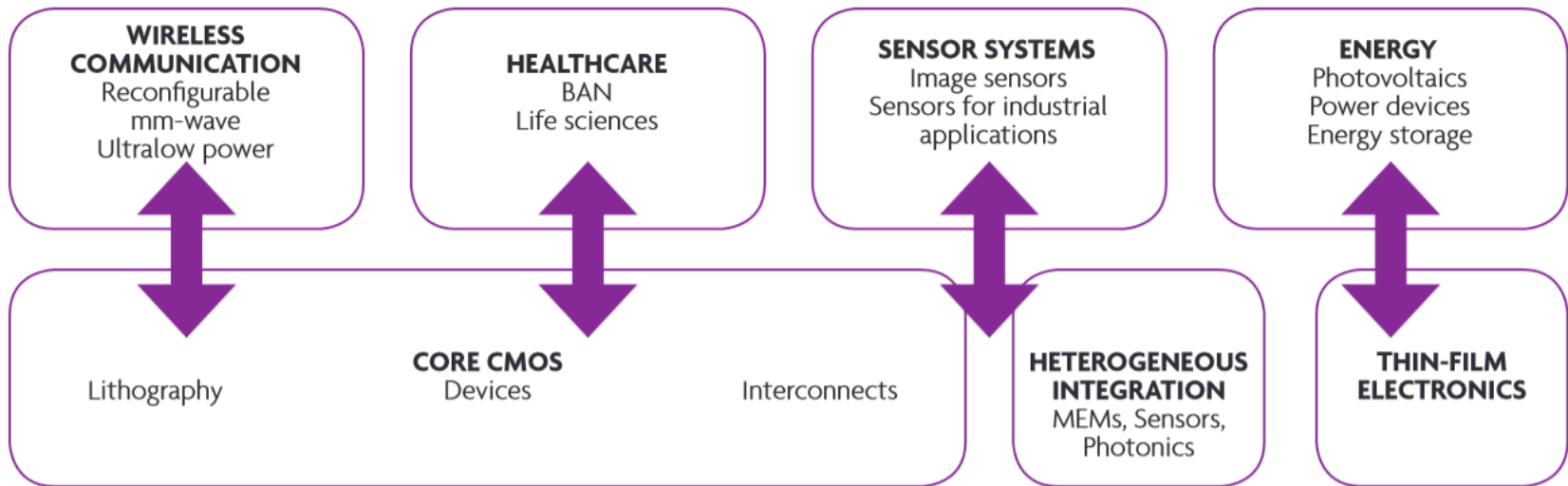
24,400 m<sup>2</sup> of office space,  
laboratories, training facilities,  
and technical support rooms



- 200 mm clean room
- 300 mm clean room (450 mm ready)
- silicon PV pilot line
- state-of-the-art laboratories for solar cell research, research on wireless communication, biomedical research and long-term brain research



# Imec's research structure



- Si PV, OPV, TF PV (CZTS, a-Si), Perovskites, multi-junctions ...



# Part I - outline

- Why  $\text{Al}_2\text{O}_3$ ?
- Spatial atomic layer deposition (ALD) of  $\text{Al}_2\text{O}_3$
- Thermal stability
- p-type PERL
- Illumination independency
- n-type PERT and  $\text{Al}_2\text{O}_3$  contact passivation / doping

*J. Vac. Sci. Technol. A (2012) DOI: 10.1116/1.4728205*

*Prog. Photovolt: Res. Appl. (2011) DOI: 10.1002/pip.1092*

*38<sup>th</sup> IEEE PVSC (2012) DOI: 10.1109/PVSC.2012.6317802*

*Sol. Energy Mater. Sol. Cells (2012) DOI: 10.1016/j.solmat.2012.01.032*

*Prog. Photovolt: Res. Appl. (2012) DOI: 10.1002/pip.2196*

*Phys. Status Solidi RRL (2012) DOI: 10.1002/pssr.201206154*

*Prog. Photovolt: Res. Appl. (2014) DOI: 10.1002/pip.2478*

*Energy Procedia (2014) DOI: 10.1016/j.egypro.2014.08.041*

*Phys. Status Solidi (a) (2013) DOI: 10.1002/pssa.201329058*

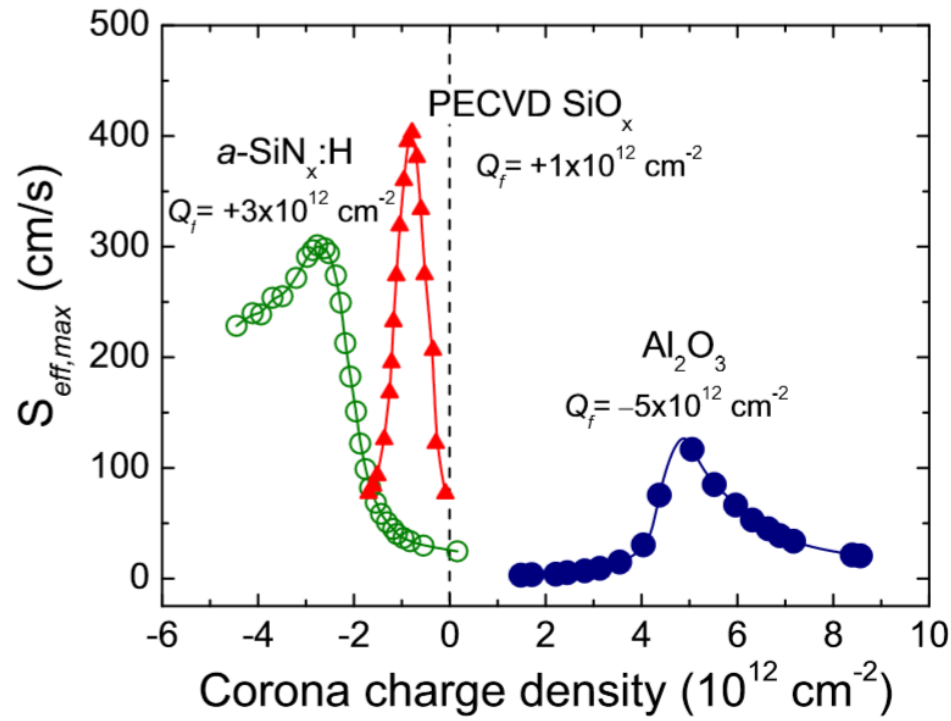




# Why Al<sub>2</sub>O<sub>3</sub>?

- Chemical passivation - Low D<sub>it</sub>
- Field effect passivation - Q<sub>f</sub> < 0

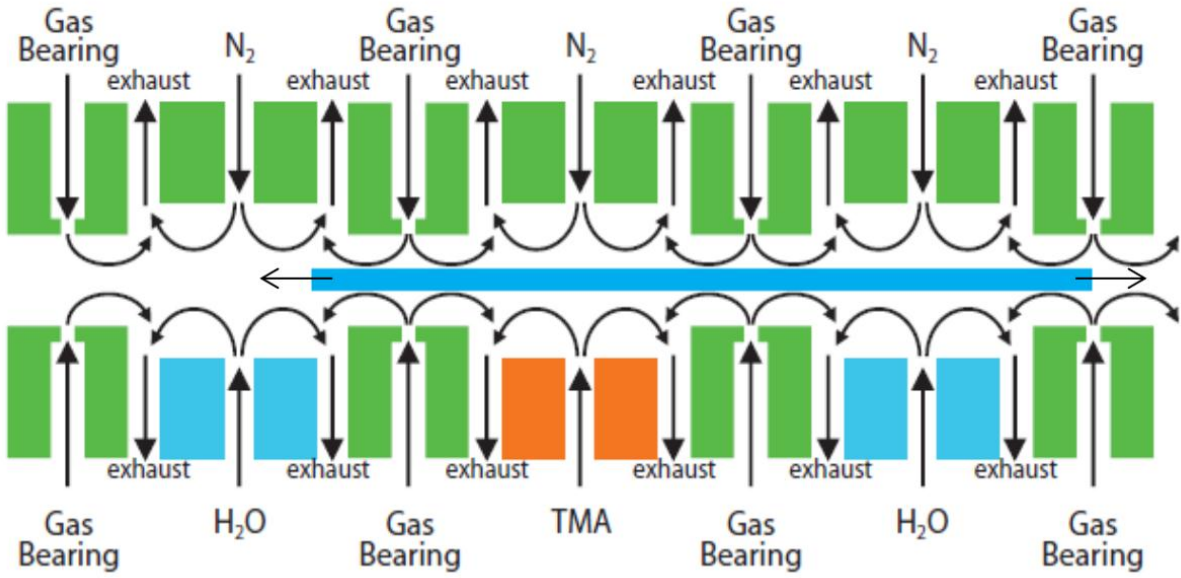
$$U_{surface} = \int_{E_V}^{E_C} \frac{v_{th}(n_s p_s - n_i^2)}{\frac{n_s + n_1(E_{it})}{\sigma_p(E_{it})} + \frac{p_s + p_1(E_{it})}{\sigma_n(E_{it})}} D_{it}(E_{it}) dE_{it}$$





# Spatial ALD $\text{Al}_2\text{O}_3$

- Atmospheric pressure
- Increased throughput and TMA efficiency compared to standard “temporal” ALD



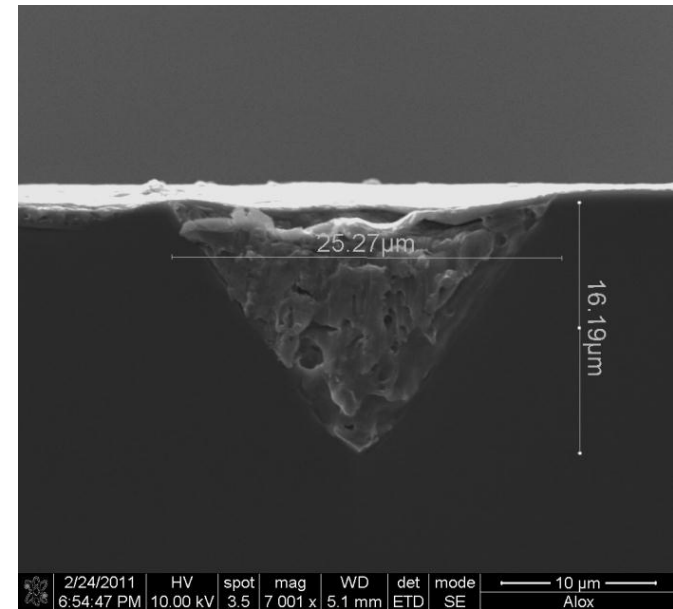
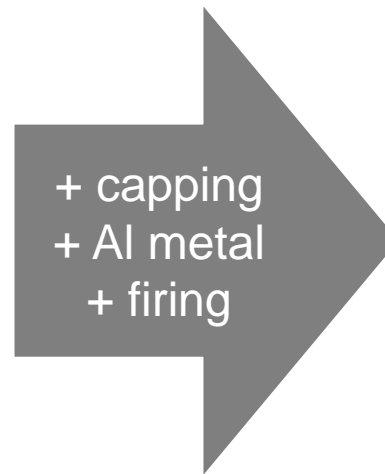
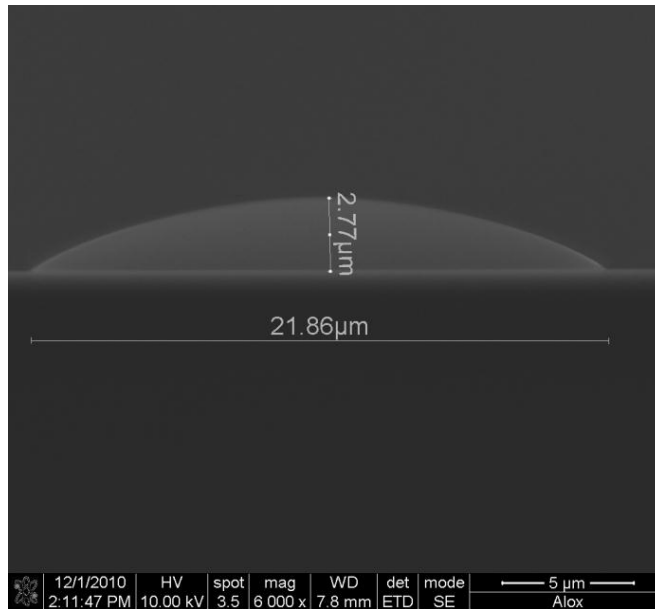
In-line  
1-side depo  
> 1 nm/s





# Thermal stability (blistering)

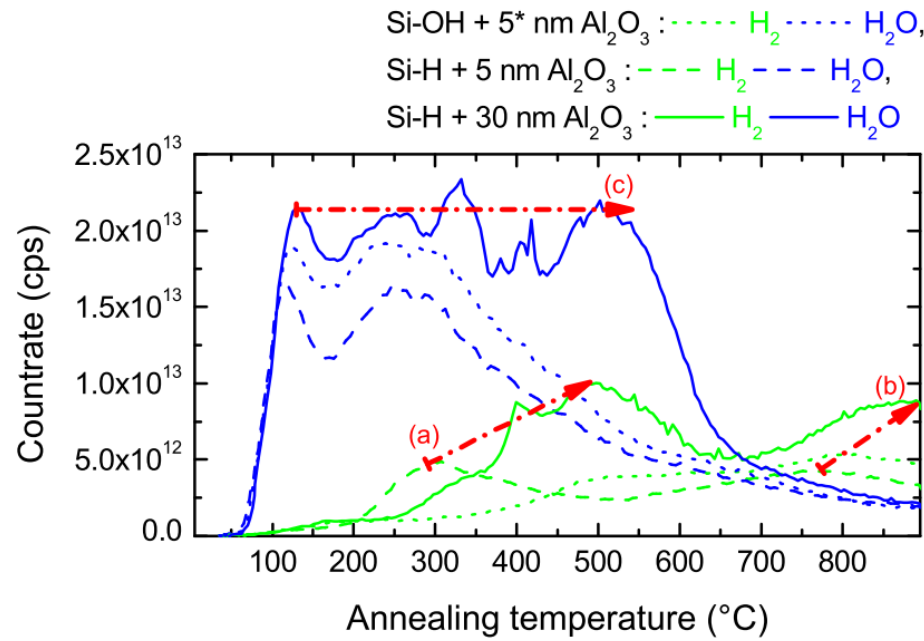
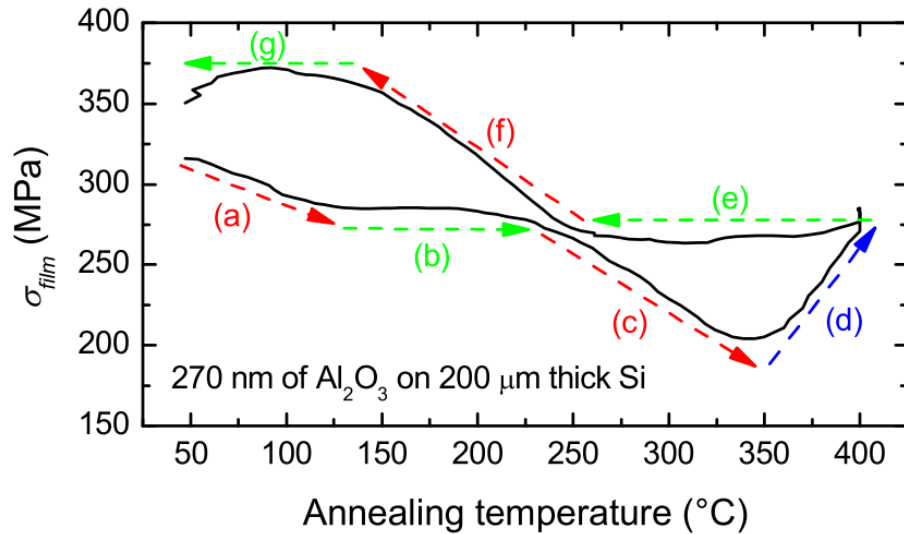
- Thick or capped (ALD)  $\text{Al}_2\text{O}_3$  films blister upon annealing
- Blisters lead to additional point contacts





# Thermal stability (blistering)

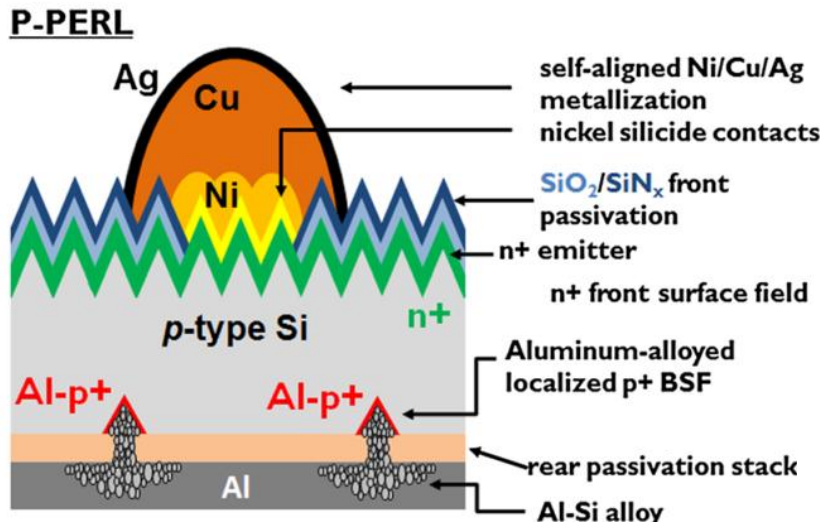
- Combination of (tensile) stress and outgassing (effusion of H<sub>2</sub>, H<sub>2</sub>O)
- Solution: thin ALD films and annealing before capping





# p-type PERL

- Rear pass. stack = spatial ALD  $\text{Al}_2\text{O}_3$  ( $\leq 10$  nm) + annealing +  $\text{SiN}_x$
- Best cell 20.5 %
  - $V_{\text{OC}} = 665$  mV;  $J_{\text{SC}} = 38.6$  mA/cm<sup>2</sup>; FF = 79.9 %
- Imec's Si PV focus moved to n-type



Similar technologies:

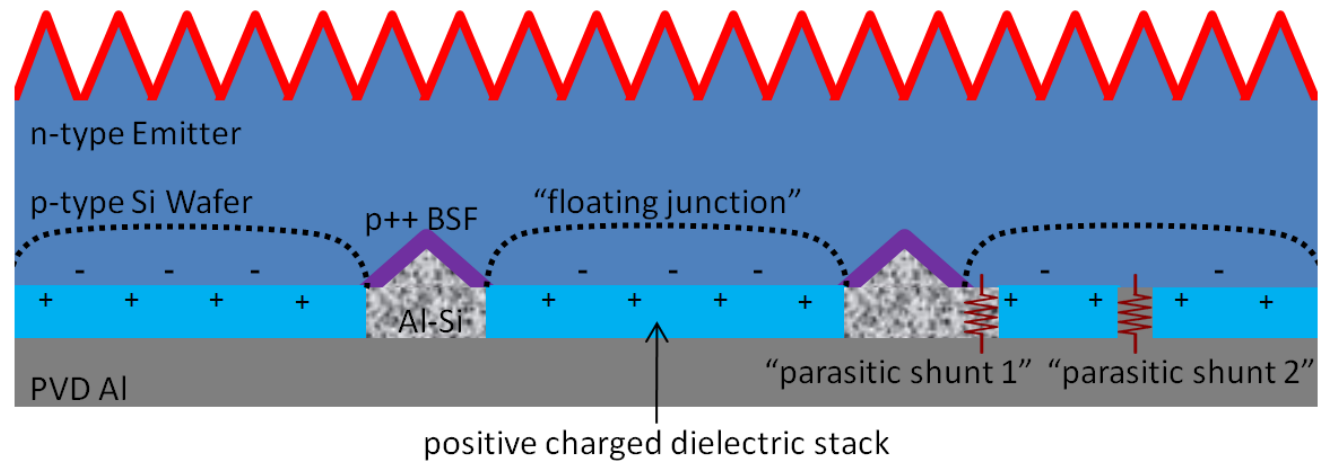
*Trina Solar*  
*Suntech*  
*Canadian Solar*  
*Ja Solar*  
*Hanwha Solar*

...



# Illumination independency

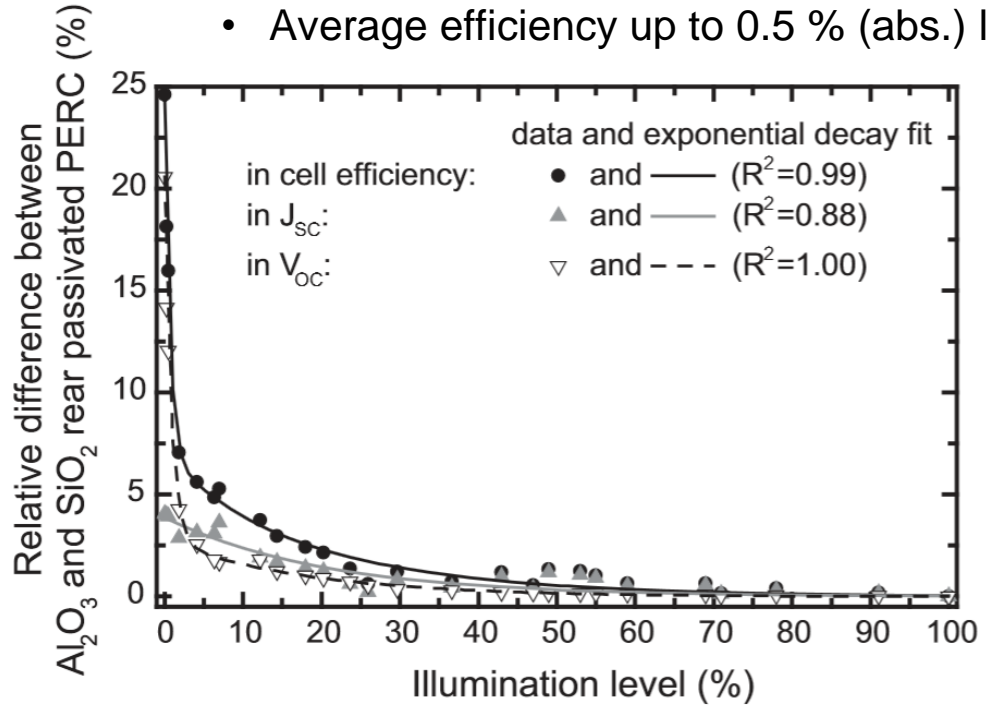
- $V_{OC}$  → pos./neg. charged surf. pass. ( $S_{eff}$ , S.R.H.)
- $J_{SC}$  → parasitic shunting
  - Rear passivation of p-type Si PERC =
    - Pos. charged dielectric → inversion = floating junction, constant loss of photo-generated  $e^-$  from the inverted region via the shunt
    - Neg. charged dielectric → accumulation





# Illumination independency

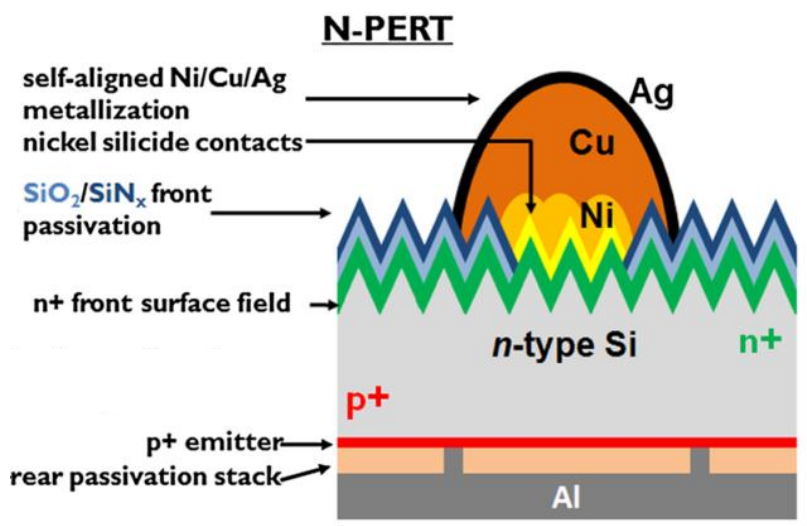
- $\text{SiO}_2$  compared to  $\text{Al}_2\text{O}_3$  rear passivated p-type Si PERC
  - Filters are used to reduce the light intensity < 100 %
- $\text{SiO}_2$  rear pass. p-Si PERC
  - Average efficiency up to 0.5 % (abs.) lower in low solar irradiation regions





# n-type PERT and contact pass. + doping

- Rear pass. stack = spatial ALD  $\text{Al}_2\text{O}_3$  ( $\leq 10$  nm) (+ ann.) +  $\text{SiN}_x$
- Best cell 21.5 %
  - $V_{OC} = 677$  mV;  $J_{SC} = 39.1$  mA/cm<sup>2</sup>; FF = 81.3 %
- Contact pass. of n<sup>+</sup>-Si & p<sup>+</sup>-doping by laser ablation of  $\text{Al}_2\text{O}_3/\text{SiN}_x$



L. Tous et al., *Prog. Photovolt: Res. Appl.* (2014) DOI: 10.1002/pip.2478  
J. Deckers et al., *Energy Procedia* (2014) DOI: 10.1016/j.egypro.2014.08.041  
N.-P. Harder, *Phys. Status Solidi (a)* (2013) DOI: 10.1002/pssa.201329058





# All of this is teamwork!

My promoter Jef Poortmans and all imec colleagues





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# Uppsala, Sweden





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# Ångström Solar Center, University of Uppsala





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# Ångström laboratiet / laboratory

- Group
  - Tunnfilmssolceller / Thin Film Solar Cells
- Department
  - Fasta Tillståndets Elektronik / Solid State Electronics





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UNIVERSITET



$$1 \text{ Ångström} = 1 \text{ Å} = 0.1 \text{ nm}$$

## Anders Jonas Ångström

From Wikipedia, the free encyclopedia

**Anders Jonas Ångström** [<sup>i</sup><sup>a</sup><sup>n</sup><sup>d</sup><sup>ə</sup><sup>ʃ</sup> <sup>j</sup><sup>uː</sup><sup>.</sup><sup>n</sup><sup>ə</sup><sup>s</sup> <sup>ˈ</sup><sup>ɔ</sup><sup>ŋ</sup><sup>.</sup><sup>s</sup><sup>t</sup><sup>r</sup><sup>ø</sup><sup>m</sup>] (13 August 1814, Lögdö, – 21 June 1874) was a [Swedish physicist](#) and one of the founders of the science of spectroscopy.<sup>[1]</sup>

### Contents [hide]

1 Biography

2 Honours

3 See also

4 Notes

5 References

6 Further reading

## Biography [edit]

Anders Angstrom was born in [Medelpad](#), he moved to, and was educated at [Uppsala University](#), where in 1839 he became [docent](#) in physics. In 1842 he went to the [Stockholm Observatory](#) to gain experience in practical astronomical work, and the following year he was appointed keeper of the [Uppsala Astronomical Observatory](#).

Becoming interested in [terrestrial magnetism](#) he made many observations of magnetic intensity and declination in various parts of Sweden, and was *charged* by the Stockholm Academy of Sciences with the task, not completed till shortly before his death, of working out the magnetic data obtained by the Swedish frigate "Eugénie" on her voyage around the world in 1851–1853.

In 1858, he succeeded Adolph Ferdinand Svanberg in the chair of physics at Uppsala. His most important work was concerned with the conduction of [heat](#) and with [spectroscopy](#). In his [optical](#) researches, *Optiska Undersökningar*, presented to the [Royal Swedish Academy of Sciences](#) in 1853, he not only pointed out that the electric spark yields two superposed spectra, one from the metal of the electrode and the other from the gas in which it passes, but deduced from [Leonhard Euler](#)'s theory of resonance that an incandescent gas emits luminous rays of the same refrangibility as those it can absorb. This statement, as Sir [Edward Sabine](#) remarked when awarding him the [Rumford medal](#) of the [Royal Society](#) in 1872, contains a fundamental principle of [spectrum analysis](#), and though overlooked for a number of years it entitles him to rank as one of the founders of spectroscopy.

From 1861 onwards, he paid special attention to the solar spectrum. His combination of the [spectroscope](#) with [photography](#) for the study of the [Solar System](#) resulted in proving that the [Sun](#)'s atmosphere contains [hydrogen](#), among other elements (1862), and in 1868 he published his great map of the normal [solar spectrum](#) in *Recherches sur le spectre solaire*, including detailed measurements of more than 1000 [spectral lines](#), which long remained authoritative in questions of wavelength, although his measurements were inexact by one part in 7000 or 8000, owing to the metre he used as a standard being slightly too short.

# Ångström Solar Center - Lab

Cell and module fabrication  
Electrical and material characterization

Scribing / lamination

ARC  $\text{MgF}_2$

EG evaporation Al/Ni/Al

(i-)ZnO(:Al) sputtering

CBD CdS

ALD (Cd-free)

CIGS co-evaporation

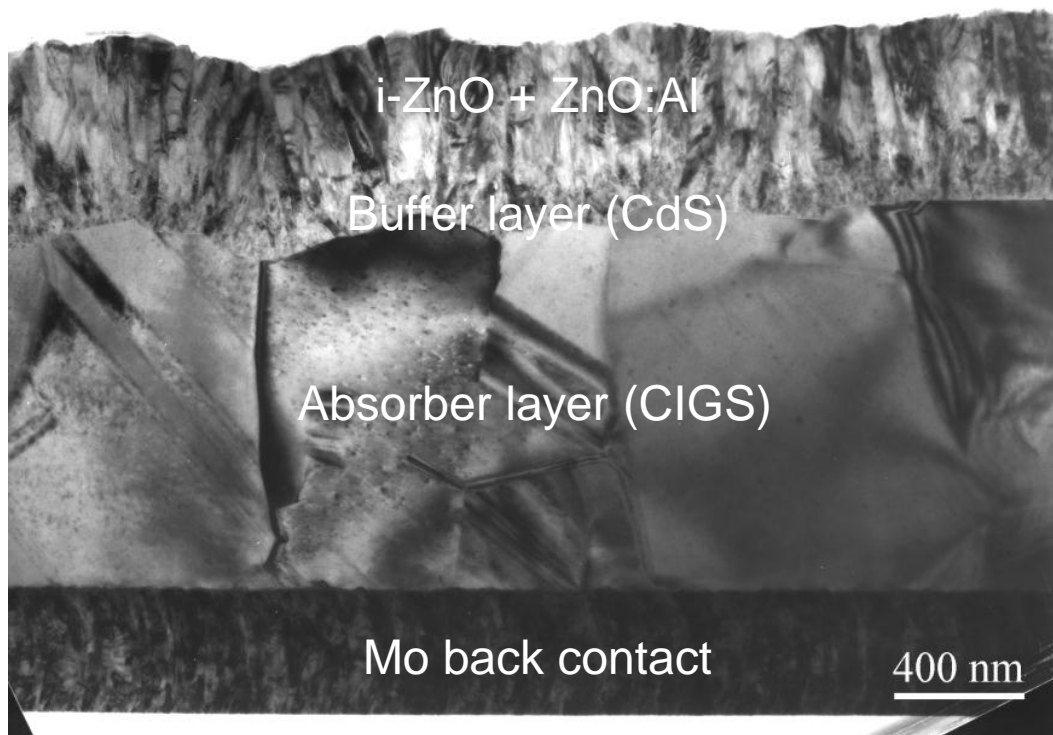
- Inline
- 2 x Batch (+ MS control)

CIGS sputtering

CZTS sputtering

NaF evaporation

Mo sputtering



Soda lime glass

# Ångström Solar Center - Goals

- CIGS solar cell  $\geq 22$  % efficiency (1-stage!)
  - Cd-free alternative buffers  $\geq 20$  %
- CZTS solar cell  $\geq 12$  % efficiency
- Back contact passivation
- Electrical modeling
- Absorber layer formation
- Module energy yield modeling
  - Focus: northern climate





## Part II - outline

- Standard CIGS solar cells
- PerCIGS = PERC meets CIGS
- $\text{Al}_2\text{O}_3$  as CIGS surface passivation
- $\text{Al}_2\text{O}_3$  rear passivated CIGS solar cells
- Contacting approaches (3)
- Na optimization in rear passivated CIGS solar cells

*Appl. Phys. Lett.* (2012) DOI: 10.1063/1.3675849

*Sol. Energy Mater. Sol. Cells* (2013) DOI: 10.1016/j.solmat.2013.07.025

*IEEE J. Photovoltaics* (2013) DOI: 10.1109/JPHOTOV.2013.2287769

*Prog. Photovolt: Res. Appl.* (2014) DOI: 10.1002/pip.2527

Uppsala University MSc. Thesis (2014) ISSN: 1650-8300, UPTEC ES14 030

*Phys. Status Solidi RRL* (2014) DOI: 10.1002/pssr.201409387

*IEEE J. Photovoltaics* (2014) in press

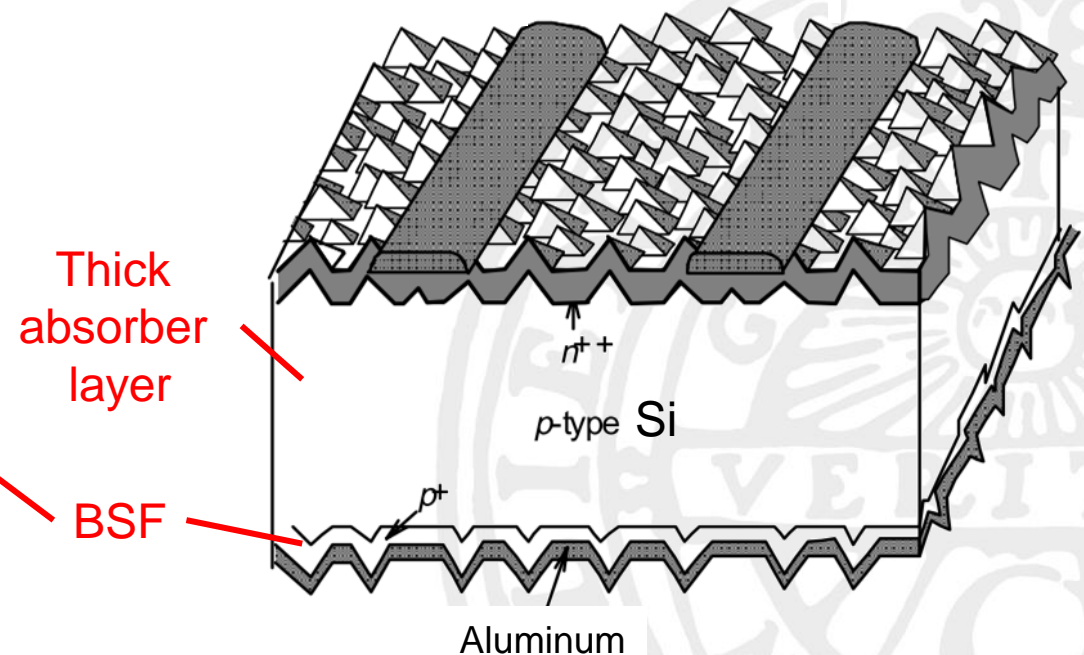
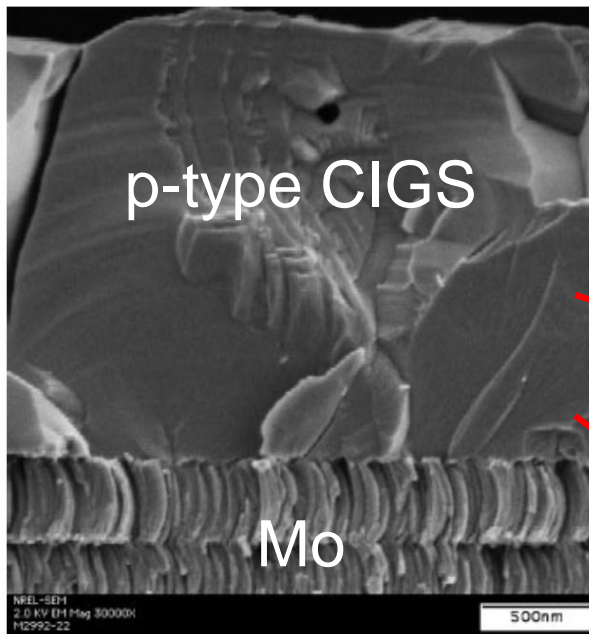
*Thin Solid Films* (2014) under review





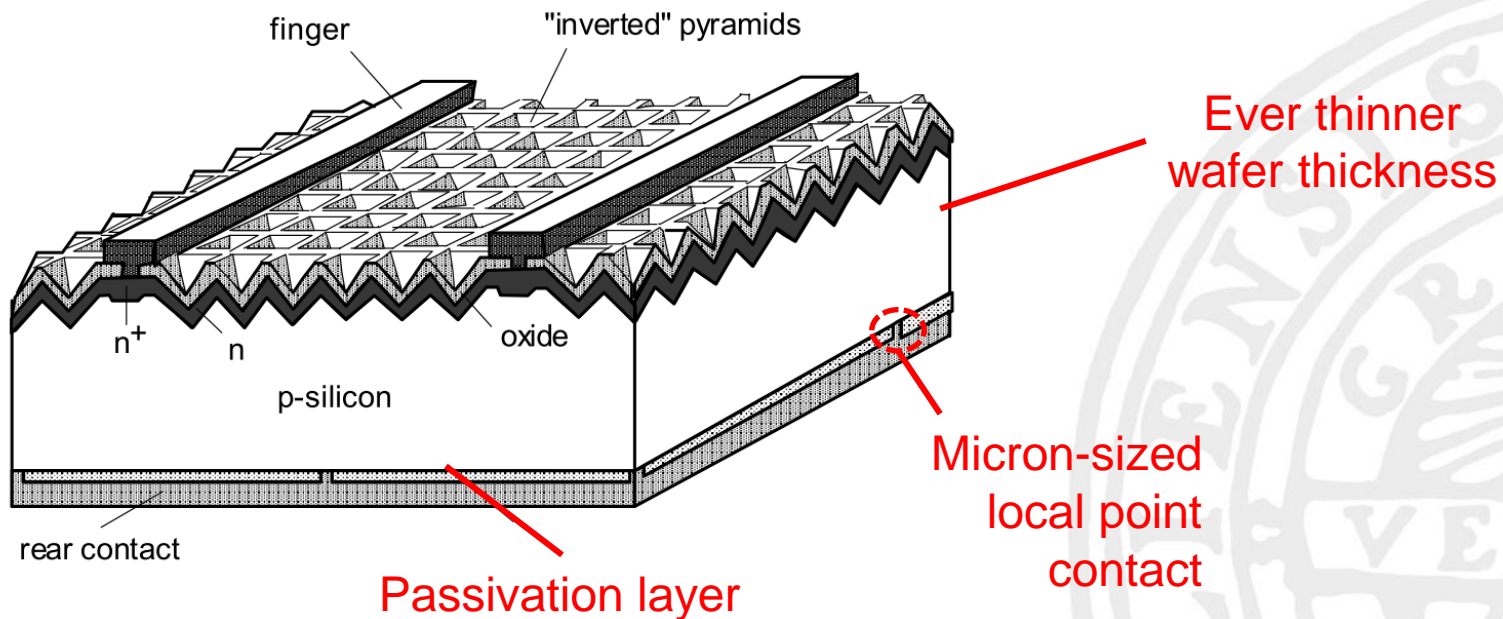
# Standard CIGS solar cells

- Back surface field (BSF) to passivate Mo/CIGS rear interface
  - Highly recombinative ( $1 \times 10^4 \text{ cm/s} \leq S_b \leq 1 \times 10^6 \text{ cm/s}$ ) and lowly reflective ( $R_b < 60 \%$ )
  - Very comparable to Al BSF in standard Si solar cells



# PercIGS = PERC meets CIGS

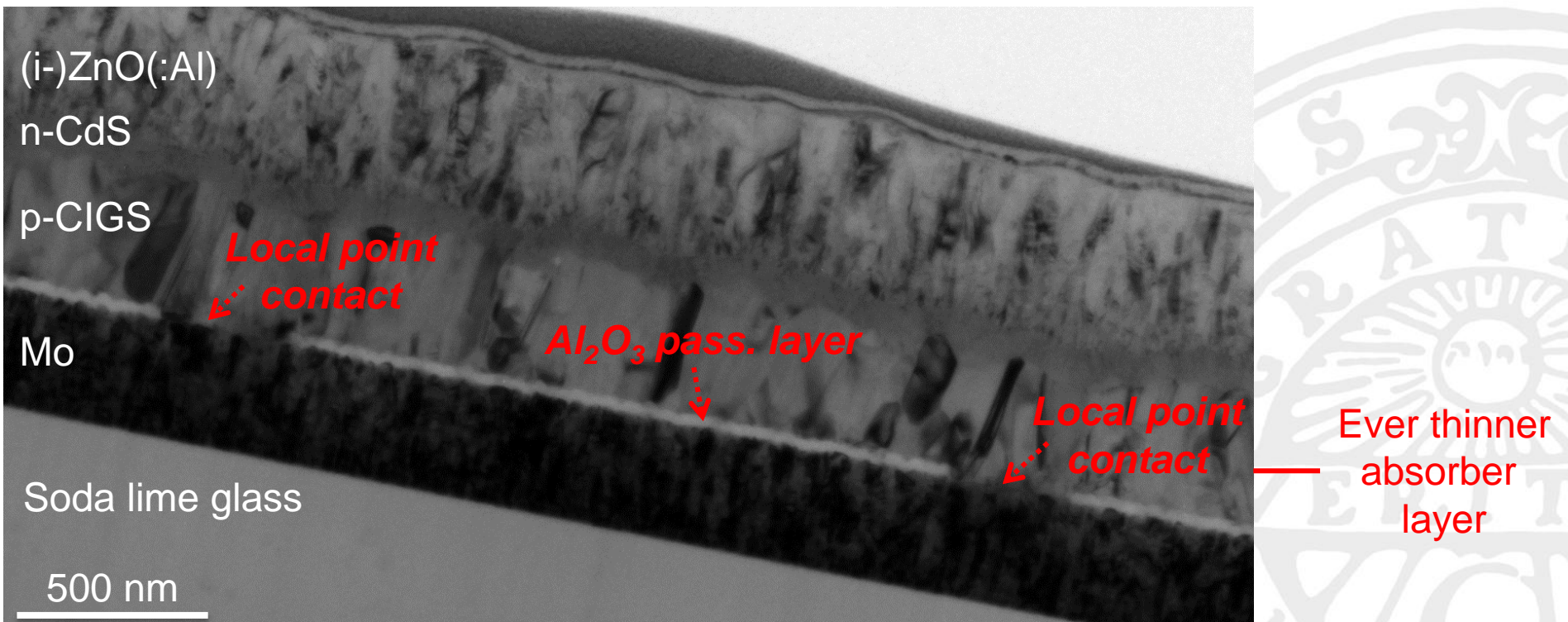
- Rear of Si PERC = a combination of an adequate rear surface passivation layer and micron-sized local point contacts





# PercIGS = PERC meets CIGS

- PercIGS = a combination of an adequate rear surface passivation layer and **nano-sized** local point contacts





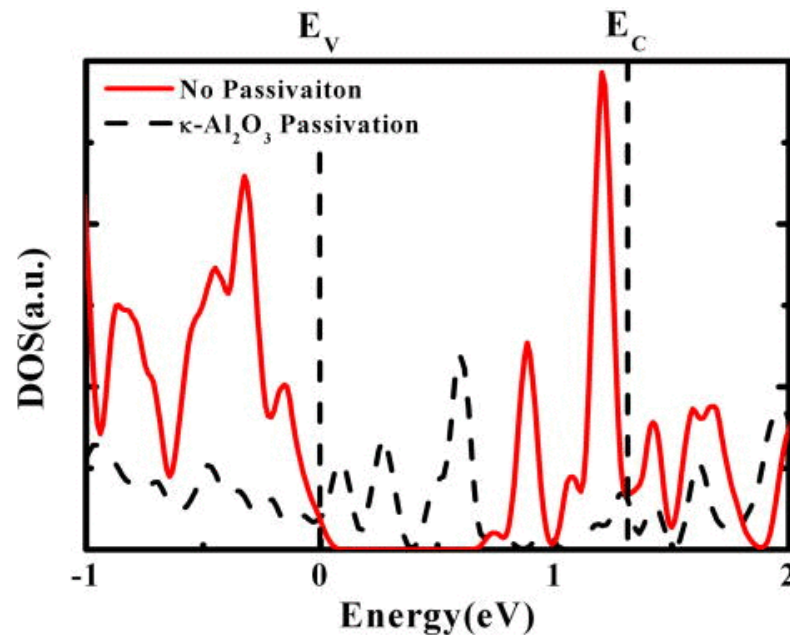
# PercIGS

- European project



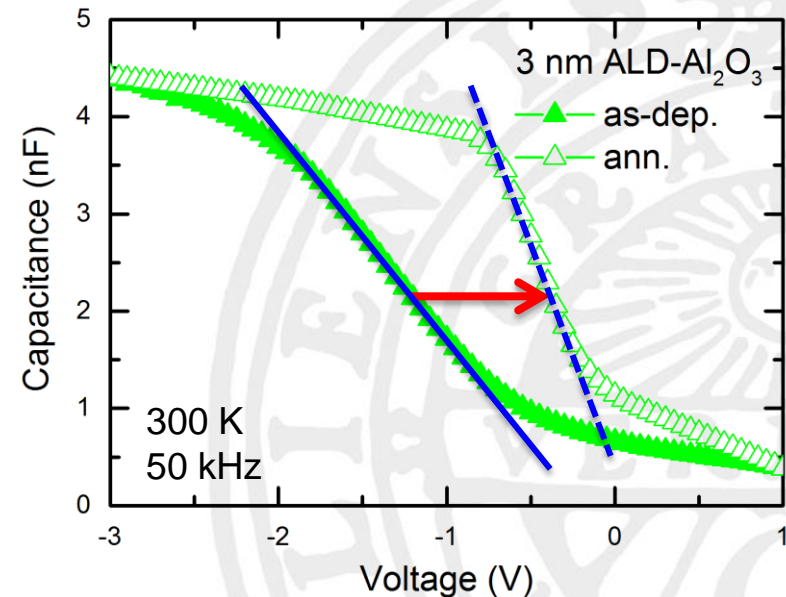
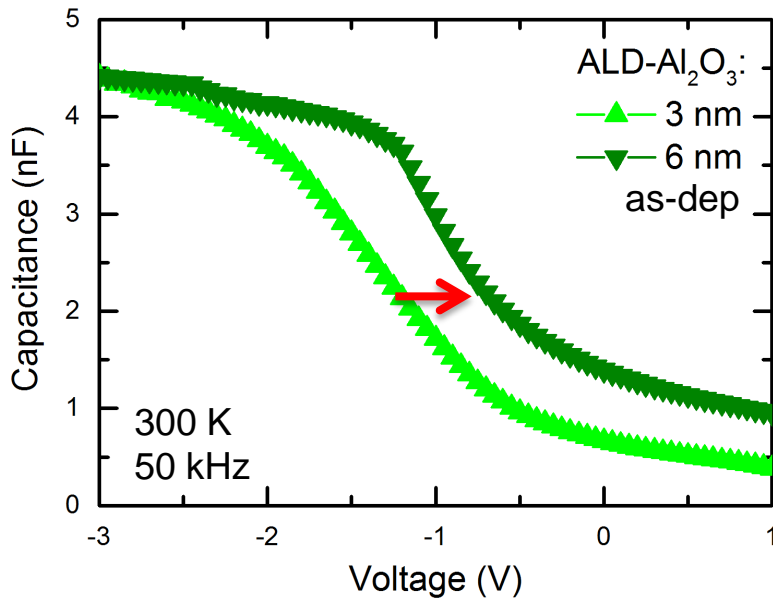
# $\text{Al}_2\text{O}_3$ as CIGS surface passivation

- Chemical passivation - Low  $D_{it}$ 
  - First principle calculations: **35 % reduction in  $D_{it}$**  as compared to unpassivated CIGS surface



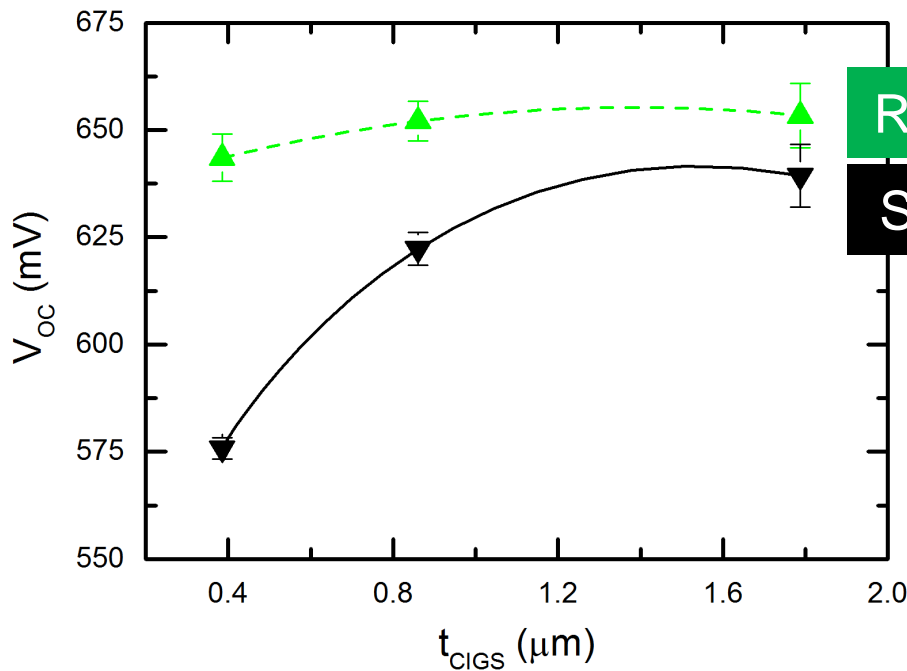
# Al<sub>2</sub>O<sub>3</sub> as CIGS surface passivation

- Field effect passivation -  $Q_f < 0$ 
  - $Q_f < 0$  – positive shift in flat-band voltage ( $V_{FB}$ ) a.f.o. Al<sub>2</sub>O<sub>3</sub> thickness
  - $\Delta Q_f < 0$  – positive shift in  $V_{FB}$  after annealing
  - Reduction in  $D_{it}$  – steeper CV slope after annealing



# $\text{Al}_2\text{O}_3$ rear passivated CIGS solar cells

- Always increase in  $V_{\text{OC}}$  compared to unpassivated standard cells
- More obvious for ever thinner  $t_{\text{CIGS}}$
- Rear surf. pass. - very comparable as “PERC  $\leftrightarrow$  std. Si solar cell”

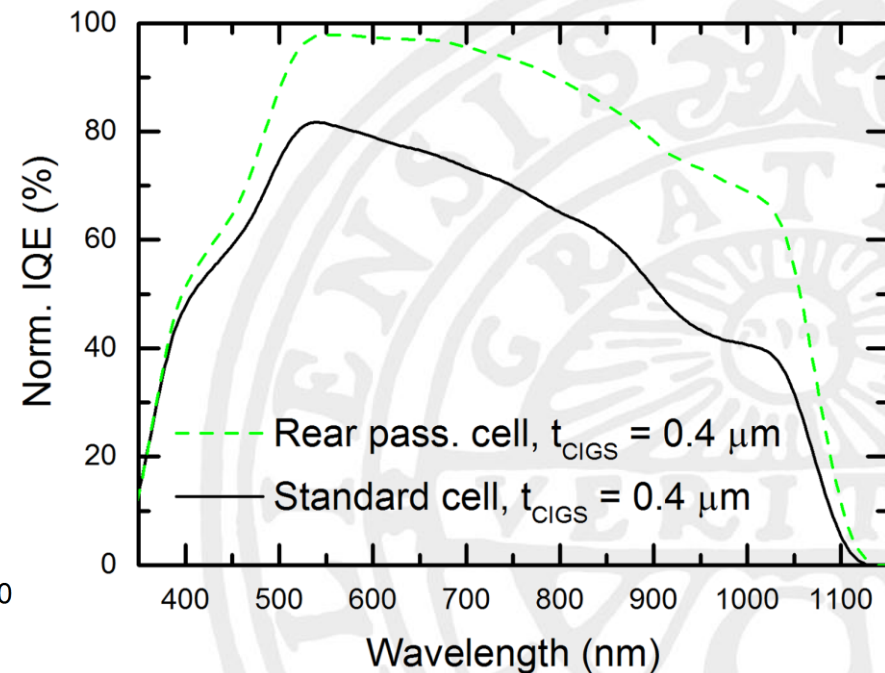
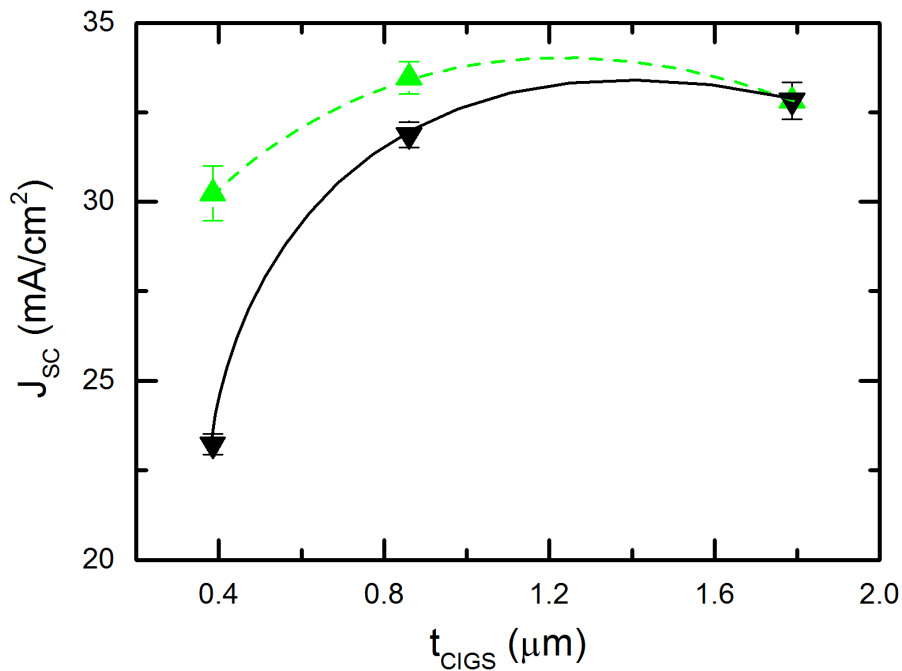


Rear pass. CIGS solar cell

Standard CIGS solar cell

# Al<sub>2</sub>O<sub>3</sub> rear passivated CIGS solar cells

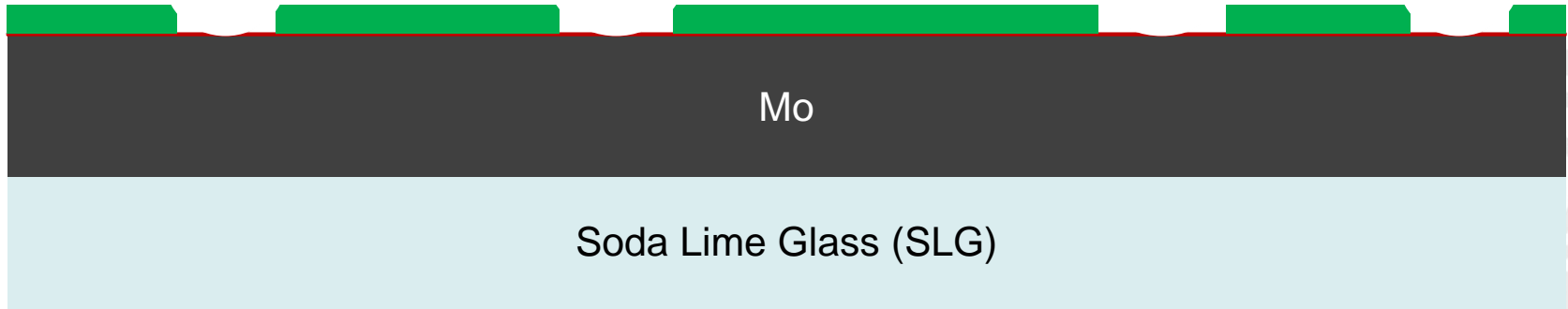
- Only increase in J<sub>SC</sub> for ever thinner t<sub>CIGS</sub>
- Still a loss in J<sub>SC</sub> compared to thick standard CIGS solar cells
- Rear int. refl. & surf. pass. - comparable as “PERC ↔ std. Si cell”





# Contacting approach 1: CdS nano-particles + removal

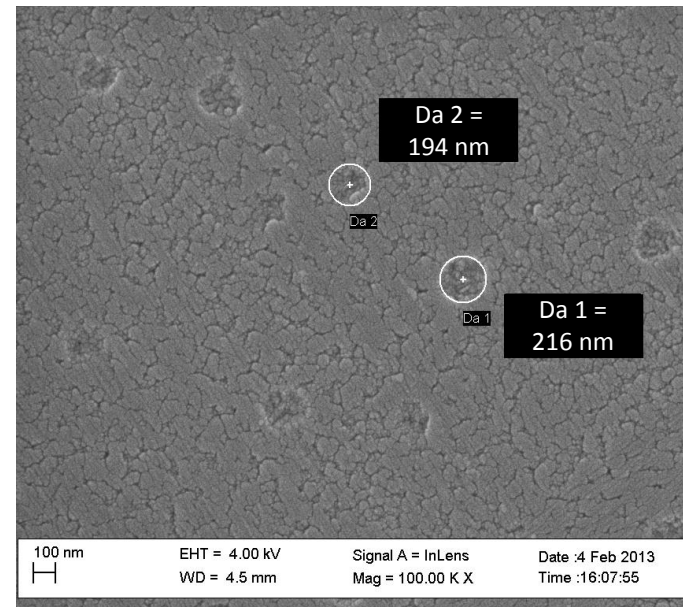
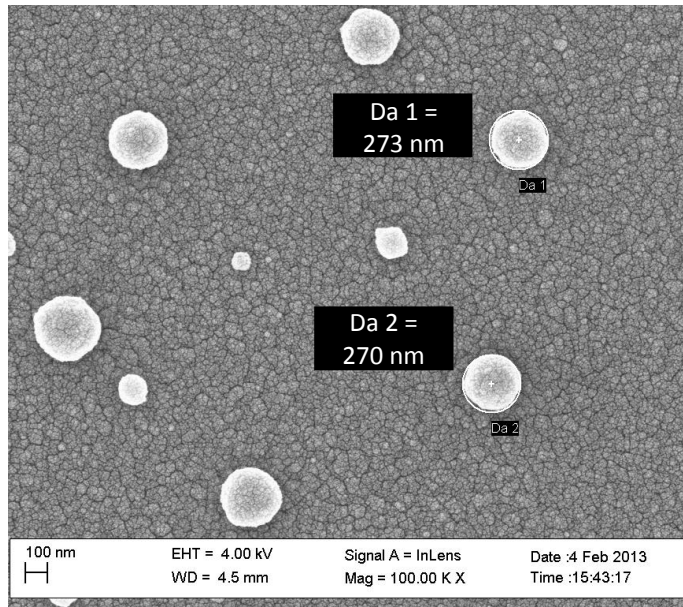
Pass.  
layer  
CdS



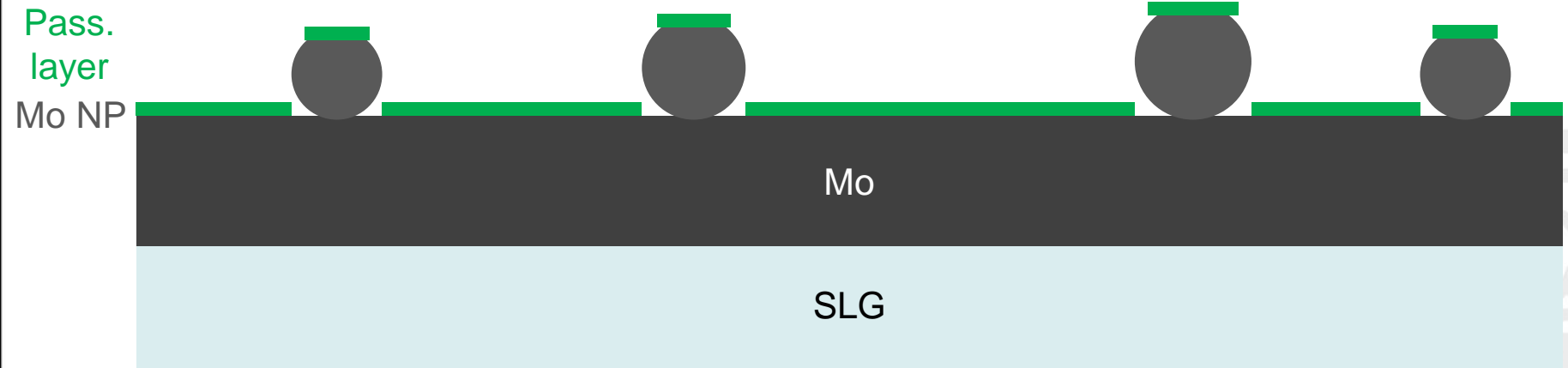
1. Deposit (chemical bath deposition = CBD) a particle-rich CdS layer on the Mo back contact
2. Deposit the surface passivation layer
  - DC-sputt.  $\text{Al}_2\text{O}_3$  or evap.  $\text{MgF}_2/\text{ALD-Al}_2\text{O}_3$
3. Remove the CdS nano-particles

# Contacting approach 1: CdS nano-particles + removal

- Particle diameter =  $285 \pm 30$  nm
- Point opening diameter =  $220 \pm 25$  nm
- High  $R_S$ , as the point contacting grids are only sub-optimized

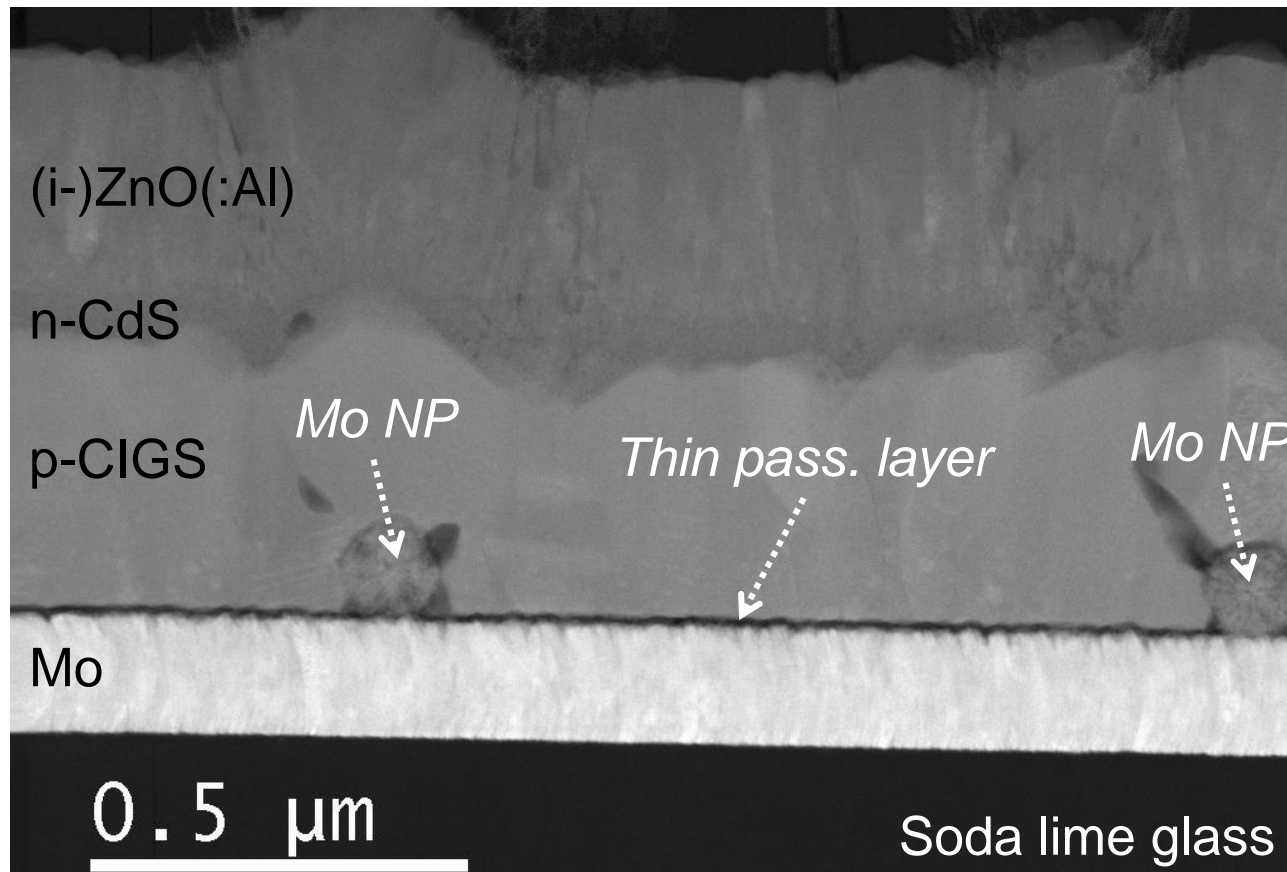


# Contacting approach 2: Mo nano-particles



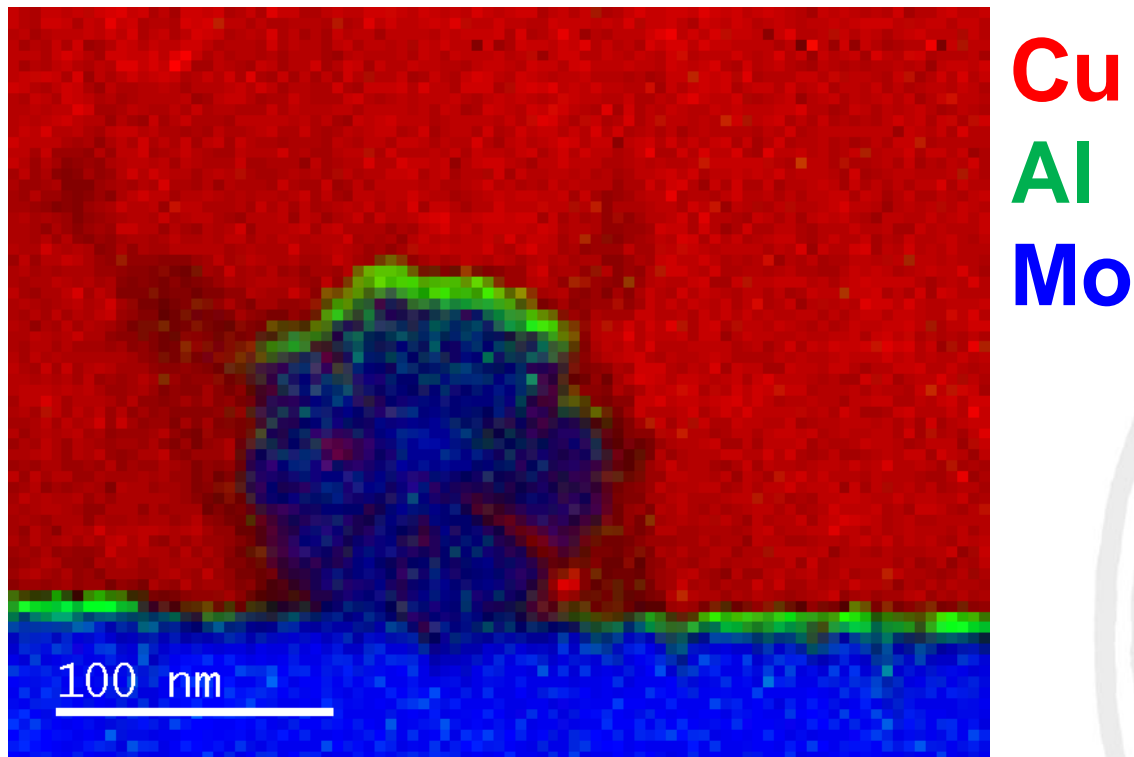
1. Deposit Mo NP (formed by a plasma process) on the Mo back contact
2. Deposit the surface passivation layer
  - DC-sputt.  $\text{Al}_2\text{O}_3$  (< 25 nm)

# Contacting approach 2: Mo nano-particles



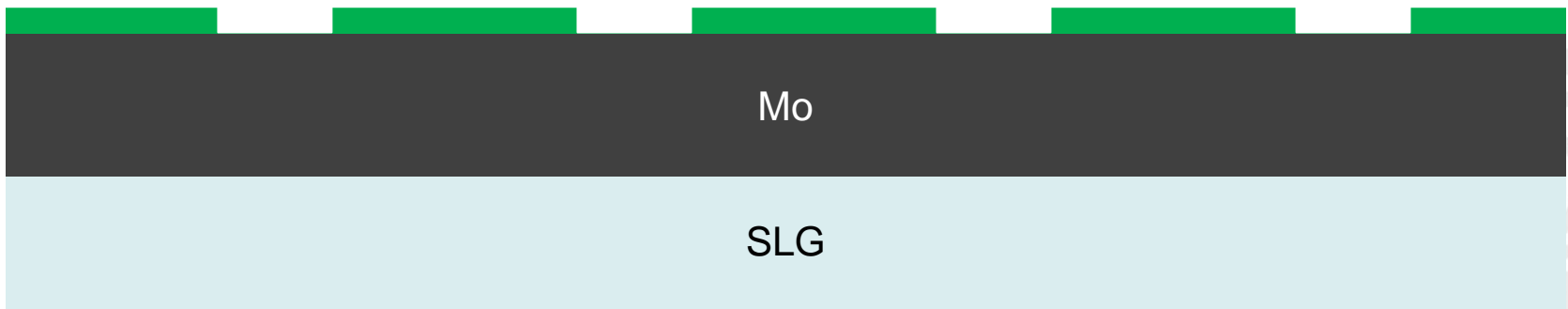
# Contacting approach 2: Mo nano-particles

- STEM-EDX picture of a finished solar cell



# Contacting approach 3: Electron beam lithography

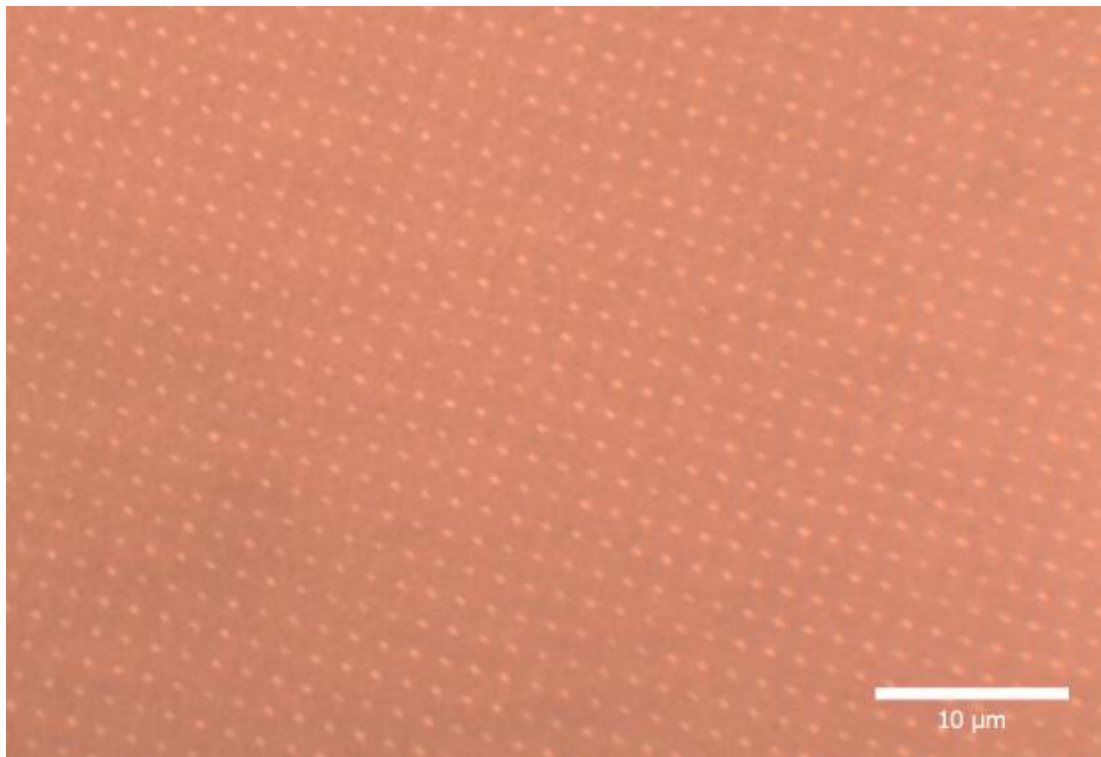
Pass.  
layer



1. Deposit the surface passivation layer
  - Sputt.  $\text{Al}_2\text{O}_3$  or ALD- $\text{Al}_2\text{O}_3$  (thick layers!)
2. Deposit the resist
3. Open the resist by e-beam litho
4. Etch the passivation layer
5. Remove the resist

# Contacting approach 3: Electron beam lithography

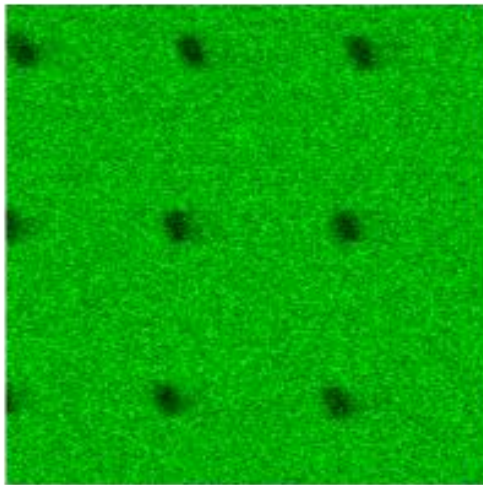
- Optical microscopy top-view picture of an opened passivation layer
  - Well-structured grid



# Contacting approach 3: Electron beam lithography

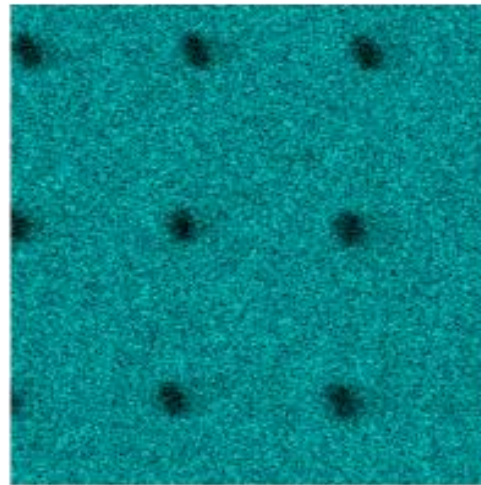
- SEM-EDX top-view picture of an opened passivation layer
  - $\text{Al}_2\text{O}_3$  etching is satisfactory

O K series



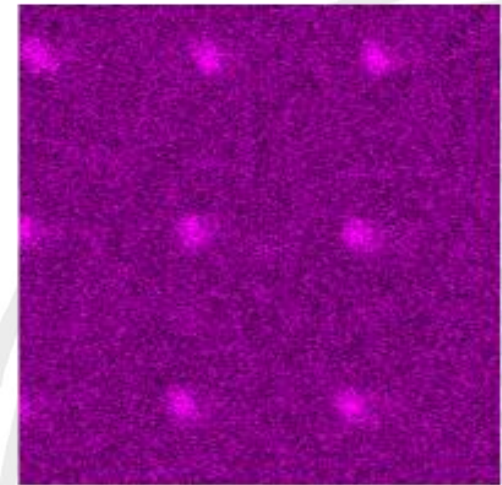
1  $\mu\text{m}$

Al K series



1  $\mu\text{m}$

Mo M series



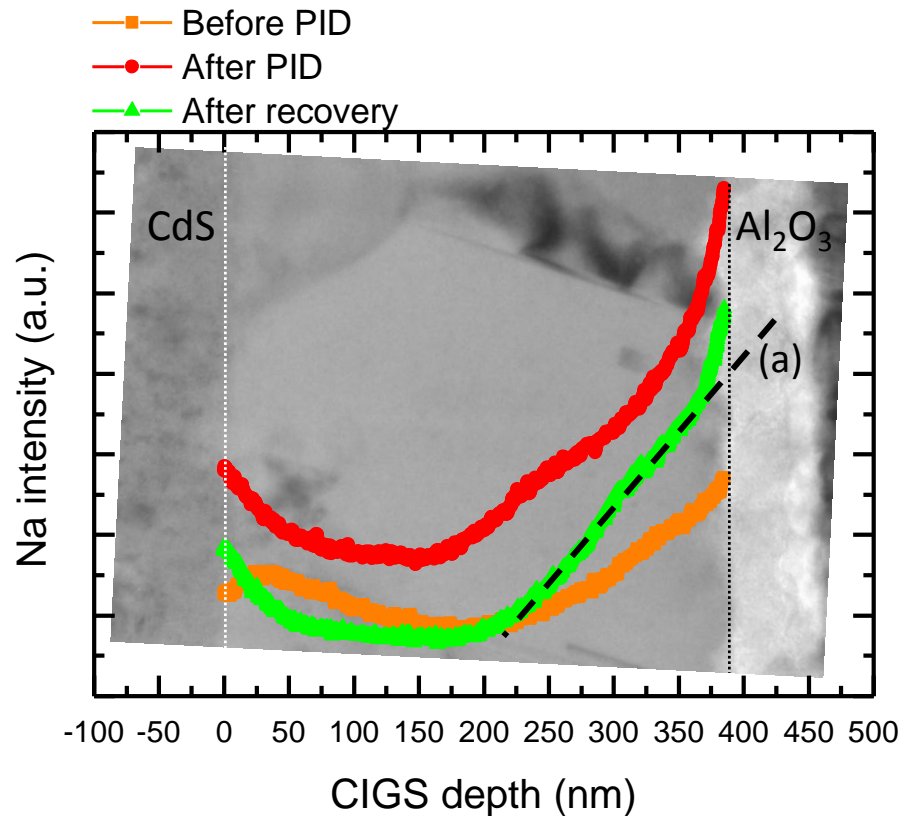
1  $\mu\text{m}$

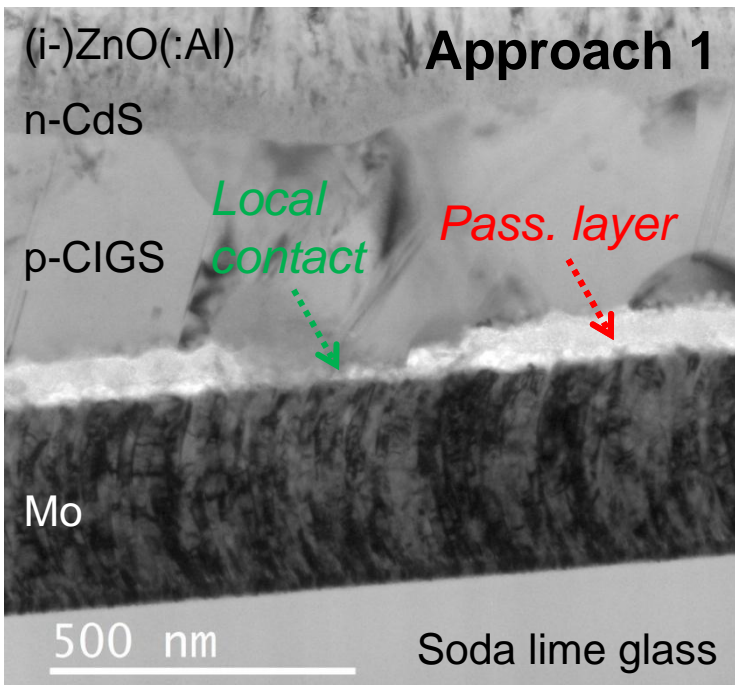
- High FF and  $V_{\text{OC}}$ 
  - Low  $R_s$



# Optimization of Na in rear passivated CIGS solar cells

- “Curing” Na-deficient cells by applying electrical fields

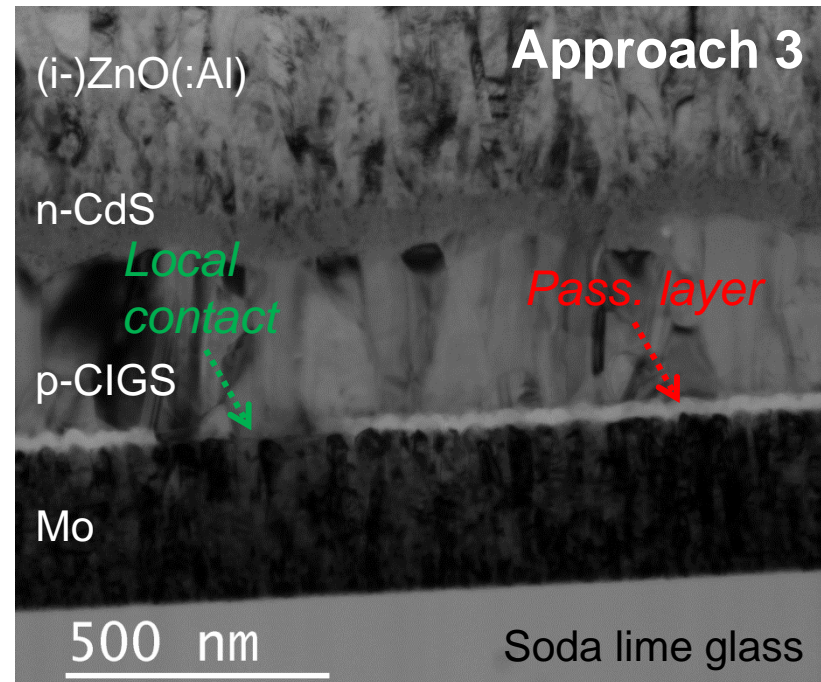
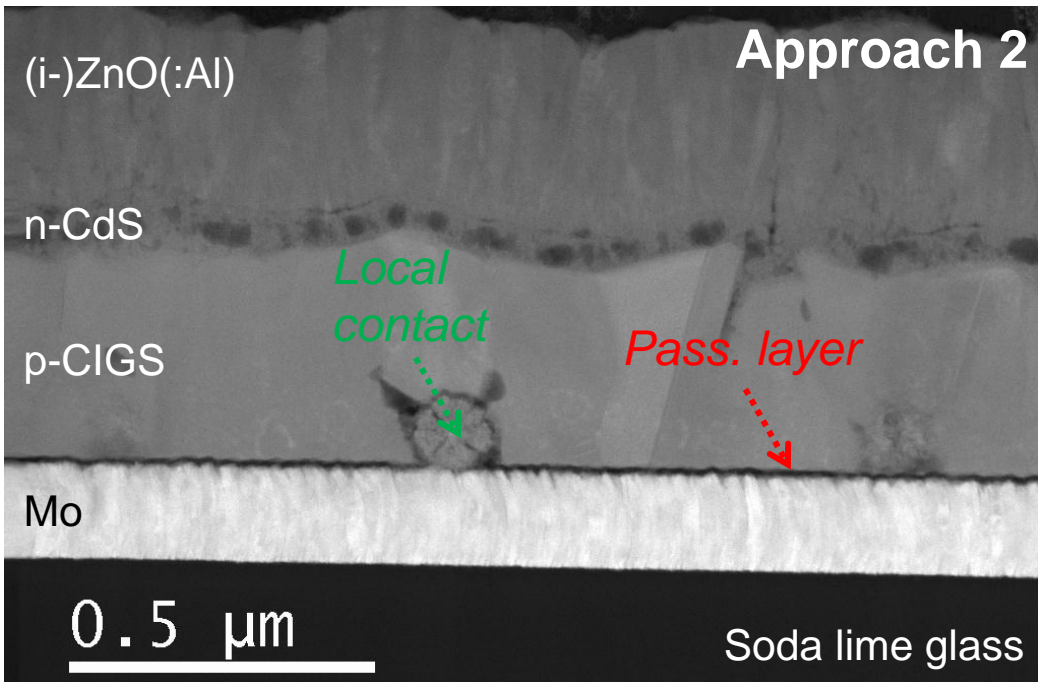




## PERC meets CIGS: PercIGS

Introduction of a **rear surface passivation layer** and **nano-sized local contacts**

Increase in  $V_{OC}$ ,  $J_{SC}$  and FF for rear surface passivated ultra-thin CIGS solar cells compared to (unpassivated) standard ultra-thin CIGS solar cells





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M. Edoff  
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*Former:*

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J. Pettersson  
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**Thank you for your  
attention!**

